

Product specification

1988 Nov 29

IC15 Data Handbook



HILIP

74F253

FEATURES

- 3-State outputs for bus interface and multiplex expansion
- Common select inputs
- Separate Output Enable Inputs

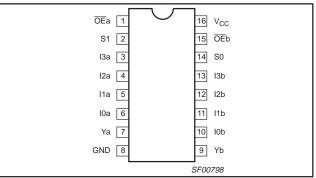
DESCRIPTION

The 74F253 has two identical 4-input multiplexers with 3-State outputs which select two bits from four sources selected by common Select inputs (S0, S1). When the individual Output Enable (\overline{OEa} , \overline{OEb}) inputs of the 4-input multiplexers are High, the outputs are forced to a high impedance (Hi-Z) state.

The 74F253 is the logic implementation of a 2-pole, 4-position switch; the position of the switch being determined by the logic levels supplied to the two common Select inputs.

To avoid exceeding the maximum current ratings when the outputs of the 3-State devices are tied together, all but one device must be in the high-impedance state. Therefore, only one Output Enable must be active at a time.

PIN CONFIGURATION



TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F253	7.0ns	12mA

ORDERING INFORMATION

	COMMERCIAL RANGE		
DESCRIPTION	V _{CC} = 5V ±10%, T _{amb} = 0°C to +70°C	PKG DWG #	
16-pin plastic DIP	N74F253N	SOT38-4	
16-pin plastic SO	N74F253D	SOT109-1	

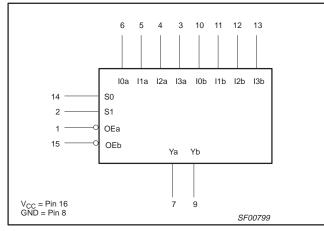
INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	74F (U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
l0a–l3a	Port A data inputs	1.0/1.0	20µA/0.6mA
l0b–l3b	Port B data inputs	1.0/1.0	20µA/0.6mA
S0, S1	Common Select inputs	1.0/1.0	20µA/0.6mA
OEa	Port A Output Enable input (active Low)	1.0/1.0	20µA/0.6mA
OEb	Port B Output Enable input (active Low)	1.0/1.0	20µA/0.6mA
Ya, Yb	3-State outputs	150/40	3mA/24mA

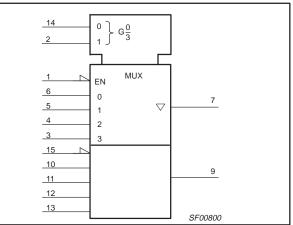
NOTE:

One (1.0) FAST unit load is defined as: 20µA in the High state and 0.6mA in the Low state.

LOGIC SYMBOL

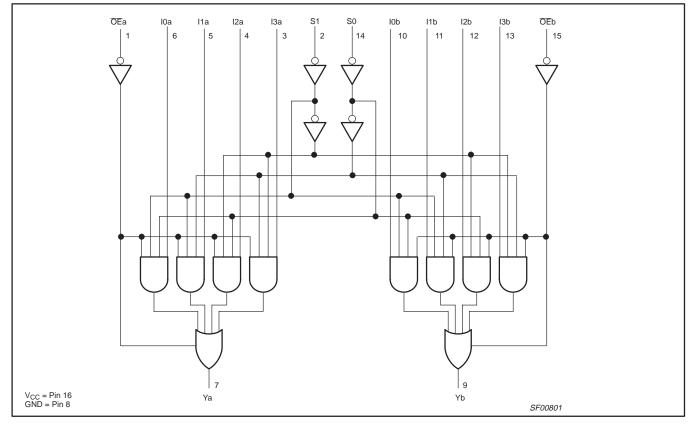


IEC/IEEE SYMBOL



74F253

LOGIC DIAGRAM



FUNCTION TABLE

			INPUTS				OUTPUT
S0	S1	10	11	12	13	ŌĒ	Y
Х	Х	Х	Х	Х	Х	Н	Z
L	L	L	Х	Х	Х	L	L
L	L	н	Х	Х	Х	L	Н
н	L	х	L	х	х	L	L
н	L	х	н	х	х	L	Н
L	н	х	Х	L	Х	L	L
L	н	х	Х	н	Х	L	Н
н	н	х	х	х	L	L	L
н	н	Х	Х	х	Н	L	Н

NOTES:

H = High voltage level L = Low voltage level X = Don't care Z = High impedance "off" state

74F253

ABSOLUTE MAXIMUM RATINGS

(Operation beyond the limit set forth in this table may impair the useful life of the device.

Unless otherwise noted these limits are over the operating free air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
V _{CC}	Supply voltage	-0.5 to +7.0	V
V _{IN}	Input voltage	-0.5 to +7.0	V
I _{IN}	Input current	-30 to +5	mA
V _{OUT}	Voltage applied to output in High output state	–0.5 to V_{CC}	V
I _{OUT}	Current applied to output in Low output state	48	mA
T _{amb}	Operating free-air temperature range	0 to +70	°C
T _{stg}	Storage temperature	-65 to +150	°C

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER		UNIT		
STWBOL	PARAMETER	MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage	4.5	5.0	5.5	V
V _{IH}	High-level input voltage	2.0			V
V _{IL}	Low-level input voltage			0.8	V
I _{IK}	Input clamp current			-18	mA
I _{OH}	High-level output current			-3	mA
I _{OL}	Low-level output current			24	mA
T _{amb}	Operating free-air temperature range	0		70	°C

74F253

DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature range unless otherwise noted.)

			TEST CONDITIONS ^{NO TAG}			LIMITS			
SYMBOL	PARAMETE	PARAMETER				TYP NO TAG	МАХ	UNIT	
M			$V_{CC} = MIN, V_{IL} = MAX,$		$\pm 10\% V_{CC}$	2.4			V
V _{OH}	High-level output voltage	;	$V_{IH} = MIN, I_{OH} = MAX$		±5%V _{CC}	2.7	3.3		V
M			$V_{CC} = MIN, V_{IL} = MAX,$		±10%V _{CC}		0.35	0.50	V
V _{OL}	Low-level output voltage		$V_{IH} = MIN, I_{OL} = MAX$		±5%V _{CC}		0.35	0.50	V
V _{IK}	Input clamp voltage		$V_{CC} = MIN, I_I = I_{IK}$				-0.73	-1.2	V
lı	Input current at maximum input voltage		$V_{CC} = MAX, V_I = 7.0V$					100	μΑ
I _{IH}	High-level input current		$V_{CC} = MAX, V_I = 2.7V$					20	μΑ
I _{IL}	Low-level input current		$V_{CC} = MAX, V_I = 0.5V$					-0.6	mA
I _{OZH}	Off-state output current High-level voltage applie	ed	$V_{CC} = MAX, V_O = 2.7V$					50	μA
I _{OZL}	Off-state output current Low-level voltage applied		$V_{CC} = MAX, V_{O} = 0.5V$				-50	μΑ	
I _{OS}	Short-circuit output current ^{NO TAG}		V _{CC} = MAX			-60		-150	mA
		I _{CCH}		OEn=GND, Sn=I			10	16	mA
I _{CC}	Supply current (total)	I _{CCL}	$V_{CC} = MAX$	OEn=Sn=In=	=GND		12	23	mA
		I _{CCZ}]	<u>OE</u> n=4.5V, S	Sn=In=GND		14	23	mA

NOTES:

1. For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.

2. All typical values are at $V_{CC} = 5V$, $T_{amb} = 25^{\circ}C$. 3. Not more than one output should be shorted at a time. For testing I_{OS} , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.

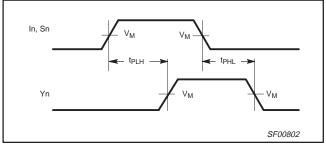
74F253

AC ELECTRICAL CHARACTERISTICS

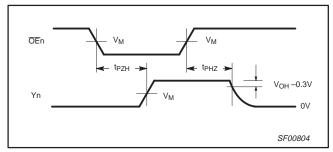
SYMBOL	PARAMETER	TEST CONDITION	T,	V _{CC} = +5V _{amb} = +25° C _L = 50pF R _L = 500Ω	C	T _{amb} = 0°(C _L =	5V ± 10% C to +70°C 50pF 500Ω	UNIT
			MIN	TYP	MAX	MIN	MAX	1
t _{PLH} t _{PHL}	Propagation delay In to Yn	Waveform NO TAG	3.0 3.0	4.5 5.0	7.0 7.0	3.0 3.0	7.5 8.0	ns
t _{PLH} t _{PHL}	Propagation delay Sn to Yn	Waveform NO TAG	4.5 5.0	7.5 8.5	10.5 11.0	4.5 4.5	11.0 12.0	ns
t _{PZH} t _{PZL}	Output Enable time to High or Low level	Waveform 2 Waveform 3	3.0 3.0	6.5 6.5	8.0 8.0	3.0 3.0	9.0 9.0	ns
t _{PHZ} t _{PLZ}	Output Disable time from High or Low level	Waveform 2 Waveform 3	2.5 2.0	3.5 3.0	5.0 5.0	2.0 1.5	6.0 6.0	ns

AC WAVEFORMS

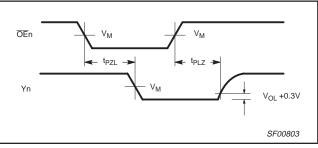
For all waveforms, V_{M} = 1.5V



Waveform 1. Propagation Deley, Data and Select to Output



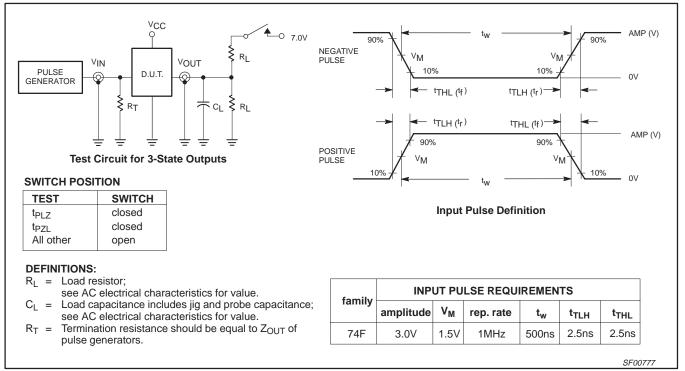
Waveform 2. 3-State Output Enable Time to High Level and Output Disable Time from High Level

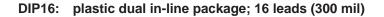


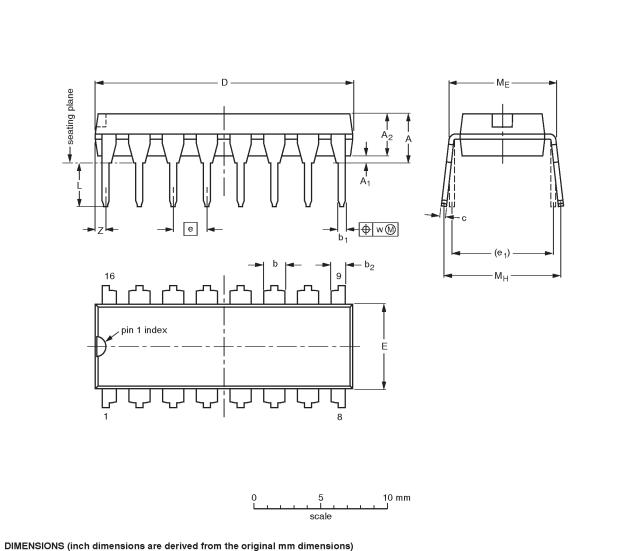
Waveform 3. 3-State Output Enable Time to Low Level and Output Disable Time from Low Level

74F253

TEST CIRCUIT AND WAVEFORMS







UNIT	A max.	A ₁ min.	A ₂ max.	b	b ₁	b ₂	c	D ⁽¹⁾	E ⁽¹⁾	е	e ₁	L	M _E	M _H	w	Z ⁽¹⁾ max.
mm	4.2	0.51	3.2	1.73 1.30	0.53 0.38	1.25 0.85	0.36 0.23	19.50 18.55	6.48 6.20	2.54	7.62	3.60 3.05	8.25 7.80	10.0 8.3	0.254	0.76
inches	0.17	0.020	0.13	0.068 0.051	0.021 0.015	0.049 0.033	0.014 0.009	0.77 0.73	0.26 0.24	0.10	0.30	0.14 0.12	0.32 0.31	0.39 0.33	0.01	0.030

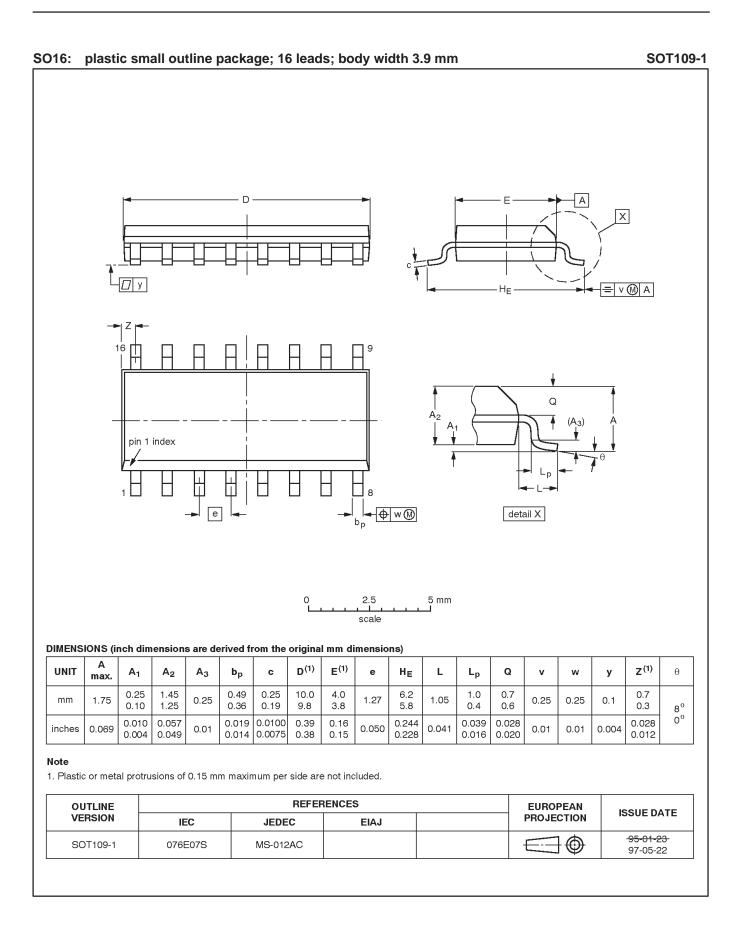
Note

1. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT38-4						-92-11-17 95-01-14

74F253

74F253



74F253

Data sheet status

Data sheet status	Product status	Definition [1]
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
Preliminary specification	Qualification	This data sheet contains preliminary data, and supplementary data will be published at a later date. Philips Semiconductors reserves the right to make chages at any time without notice in order to improve design and supply the best possible product.
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[1] Please consult the most recently issued datasheet before initiating or completing a design.

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Limiting values definition - Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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